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MOTOROLA lacksquare Semiconductor lacksquare**TECHNICAL DATA**

Advance Information

TMOS E-FET™

Power Field Effect Transistor N-Channel Enhancement-Mode Silicon Gate

This advanced TMOS E-FET is designed to withstand high energy in the avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for low voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional safety margin against unexpected voltage transients

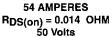
- Avalanche Energy Specified
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- IDSS and VDS(on) Specified at Elevated Temperature

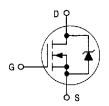


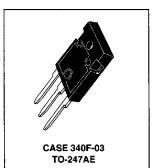
TMOS POWER FET

MTW54N05E

Motorola Preferred Device







MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit	
Drain-Source Voltage	V _{DSS}	V _{DSS} 50		
Drain-Gate Voltage ($R_{GS} = 1.0 M\Omega$)	V _{DGR}	50	Vdc	
Gate-Source Voltage — Continuous	V _G s	±20	Vdc	
Drain Current — Continuous @ $T_C = 25^{\circ}C$ — Continuous @ $T_C = 100^{\circ}C$ — Single Pulse ($t_p \le 10 \ \mu s$)	I _D	54 37 220	Adc Apk	
Total Power Dissipation @ T _C = 25°C Derate above 25°C	PD	210 1.43	Watts W/°C	
Operating and Storage Temperature Range	T _J , T _{Stg}	-55 to 150	°C	
Single Pulse Drain-to-Source Avalanche Energy — Starting T $_{\rm J}$ = 25°C (VDD = 50 Vdc, VGS = 10 Vpk, I $_{\rm L}$ = 54 Apk, L = 0.44 mH, RG = 25 $_{\rm M}$)	EAS	640	mJ	
Thermal Resistance — Junction to Case — Junction to Ambient	R ₀ JC R ₀ JA	0 7 80	°C/W	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	TL	260	°C	

This document contains information on a new product. Specifications and information are subject to change without notice

E-FET is a trademark of Motorola Inc.

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Preferred devices are Motorola recommended choices for future use and best overall value

MTW54N05E

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

· · · · · · · · · · · · · · · · · · ·	racteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					_	
Drain-Source Breakdown Voltage (V _{GS} = 0 V, I _D = 250 μAdc) Temperature Coefficient (Positive)	BV _{DSS}	50 —		_	Vdc mV/°C
Zero Gate Voltage Drain Current $(V_{DS} = 50 \text{ Vdc}, V_{GS} = 0)$ $(V_{DS} = 40 \text{ Vdc}, V_{GS} = 0, T_{J} = 1)$	25°C)	IDSS			10 100	μAdc
Gate-Body Leakage Current (VGS	= ±20 Vdc, V _{DS} = 0)	IGSS		_	100	nAdc
ON CHARACTERISTICS*						
Gate Threshold Voltage (VDS = VGS, ID = 250 μAdc) Temperature Coefficient (Negativ	re) (T _J = 125°C)	VGS(th)	2.0 1.5	3.0 —	4.0 3.5	Vdc mV/°C
Static Drain-Source On-Resistance	(V _{GS} = 10 Vdc, I _D = 27 Adc)	R _{DS(on)}	_	_	0.014	Ohm
Drain-Source On-Voltage ($V_{GS} = 1$ ($I_D = 54$ Adc) ($I_D = 27$ Adc, $T_J = 125$ °C)	0 Vdc)	V _{DS(on)}	_	_	1.0 0.8	Vdc
Forward Transconductance (VDS =	= 10 Vdc, I _D = 27 Adc)	9FS	31	_	_	mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance	(V _{DS} = 25 Vdc, V _{GS} = 0, f = 1.0 MHz)	C _{ISS}	_	4500	6300	pF
Output Capacitance		Coss	-	2300	3200	
Reverse Transfer Capacitance	· · · · · · · · · · · · · · · · · · ·	C _{rss}		750	1050	
SWITCHING CHARACTERISTICS*						
Turn-On Delay Time	$(V_{DD} = 25 \text{ Vdc, I}_D = 54 \text{ Adc,} \ V_{GS} = 10 \text{ Vdc,} \ R_g = 9.1 \Omega)$	^t d(on)		30	60	ns
Rise Time		t _r	<u> </u>	280	560	
Turn-Off Delay Time		td(off)	_	165	330	
Fall Time		t _f	-	270	550	
Gate Charge	(V _{DS} = 40 Vdc, I _D = 54 Adc, V _{GS} = 10 Vdc)	Qg	_	150	190	пC
Gate-Source Charge		Q _{gs}	_	40		
Gate-Drain Charge	143 /1 /14/	Q _{gd}	-	65	<u> </u>	1
SOURCE-DRAIN DIODE CHARACT	ERISTICS*					
Forward On-Voltage	$(I_S = 54 \text{ Adc}, V_{G\hat{S}} = 0)$ $(I_S = 6.0 \text{ Adc}, V_{GS} = 0, T_J = 125^{\circ}\text{C})$	V _{SD}	-	— 0.6	_ 1.2	Vdc
Reverse Recovery Time	(I _S = 54 Adc, V _{GS} = 0, dl _S /dt = 100 A/µs)	t _{rr}	_	150	_	ns
NTERNAL PACKAGE INDUCTANC	E					
Internal Drain Inductance (Measured from the drain lead 0	25" from package to center of die)	LD		5.0	_	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad)		LS		13	_	nH

Pulse Test Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%

[†]Switching characteristics are independent of operating junction temperature